

Special Issue

Radiation and Environmental Effects on Electronic Devices: Reliability, Failure, and Protection

Message from the Guest Editor

Electronic devices are increasingly used in harsh environments such as space, aviation, nuclear facilities, and industrial sectors. These conditions expose systems to radiation, extreme temperatures, humidity, and mechanical shock, all of which threaten device reliability. Such stressors can cause material degradation, transient faults, and permanent failures. Radiation may trigger single-event upsets (SEUs), latch-up, total ionizing dose (TID) effects, and displacement damage (DD), putting critical systems at risk. This Special Issue invites original research and reviews focusing on failure mechanisms, mitigation techniques, protective designs, and testing standards that improve electronic reliability in extreme conditions. We invite you to contribute your work and be part of advancing the reliability of electronics in demanding environments. Submit your manuscript today and help shape the future of robust electronic systems.

Guest Editor

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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